

AMENDMENT AND PRESENTATION OF CLAIMS

Please replace all prior claims in the present application with the following claims, in which claims 1-10 are currently amended.

1. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system for measuring a device under test (19), comprising:
a measuring-device unit (2); and
at least one high-frequency module (3, 24, 25), wherein each high-frequency module (3, 24, 25) ~~can be~~ is placed spatially ~~separately~~ separated from the measuring-device unit (2) and each high-frequency module (3, 24, 25) ~~can be~~ is connected to the measuring-device unit (2) via a digital interface (23, 26, 27), wherein
characterised in that
~~the processing of input data to form a bitstream to be transmitted for transmission via the digital interface (26) takes place by~~ includes assigning ~~the~~ symbols to states in ~~the~~ a state diagram of an the I-Q (in phase – quadrature phase) level in the measuring-device unit (2), or
~~and/or that a digitised~~ digitized intermediate-frequency signal is transmitted via the digital interface (27).
2. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim 1, wherein
characterised in that
the at least one high-frequency module (3, 24, 25) comprises a transmitter device ~~and/or~~ or a receiver device (28, 29) for communication with a the device under test (19).
3. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim 1 ~~or 2~~, wherein
characterised in that
the digital interface (23, 26, 27) is a serial interface.

4. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim 1 ~~or 2~~, wherein
~~characterised in that~~
the digital interface (23, 26, 27) is a parallel interface.
5. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim any one of claims 1 to 4, wherein
~~characterised in that~~
the digital interface (23, 26, 27) is an optical interface.
6. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim any one of claims 1 to 4, wherein
~~characterised in that~~
the digital interface (23, 26, 27) is an electrical interface.
7. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim any one of claims 1 to 6, wherein
~~characterised in that~~
the at least one high-frequency module (3, 24, 25) is supplied with electrical energy via a power-supply unit (14, 40) independent from the measuring-device unit (2).
8. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim any one of claims 1 to 7, wherein
~~characterised in that~~
~~several~~ a plurality of identical ports (5.1, 5.2, 5.3) are provided on the measuring-device unit (2) for the digital interface (23).
9. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim any one of claims 1 to 8, wherein
~~characterised in that~~
~~several~~ a plurality of different ports (5.1, 5.2, 5.3, 6.1, 6.2, 6.3) are provided on the measuring-device unit for the digital interface (23).

10. (Currently Amended) A high-frequency ~~High-frequency~~ measuring system according to claim any one of claims 1 to 9, wherein
characterised in that
control data or and/or user data is ~~can be~~ transmitted in a standardized ~~standardised~~ form via the digital interface, and ~~that~~ wherein the at least one high-frequency module (24') comprises means for processing a high-frequency signal with regard to the transmission of data in standardized ~~standardised~~ form via the digital interface or and/or for processing the data transmitted in standardized ~~standardised~~ form with regard to at least one predetermined ~~given~~ transmission standard for the high-frequency signal.